

<b>Notice of References Cited</b>	Application/Control No. 09/238,261	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Annan Q. Shang	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,872,588	02-1999	Aras et al.	725/14
	B	US-6,298,482	10-2001	Seidman et al.	725/101
	C	US-5,798,785	08-1998	Hendricks et al.	725/46
	D	US-5,535,206	07-1996	Bestler et al.	370/458
	E	US-6,462,832	10-2002	Malik, Naeem Iobal	358/1.15
	F	US-6,546,006	04-2003	Fraser, Alexander Gibson	370/359
	G	US-5,960,348	09-1999	Eisdorfer et al.	455/445
	H	US-5,675,635	10-1997	Vos et al.	379/112.01
	I	US-5,382,970	01-1995	Kiefl, John B.	455/2.01
	J	US-5,767,895	06-1998	Yashiro et al.	725/106
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.